



JSM-IT300

New Generation JEOL Scanning Electron Microscope

- Extended low vacuum capability as standard
(650 Pa)
- New charge-free scanning modes
- New faster, quieter, high-load stage
(2 kg tilted to 90°)
- Even more accessory ports
[EDS/WDS/EBSD working distance of 10 mm]
- High resolution frame store (5120 x 3920) as standard
- High reliability

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